



Substitute for Form 1449B/PTO

INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(use as many sheets as necessary)

Complete if Known

Application Number	10/695,019
Filing Date	October 29, 2003
First Named Inventor	Douglas S. McGregor, et al.
Group Art Unit	2878
Examiner Name	
Attorney Docket Number	UOM 0316 PUSP

Sheet 1 of 1

OTHER PRIOR ART -- NON PATENT LITERATURE DOCUMENTS

Examiner Initials	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
(G)		MCGREGOR, DOULGAS S., ET AL., Bulk GaAs-Based Neutron Detectors For Spent Fuel Analysis, Proceedings of ICONE 8, 8 th Int'l Conf. on Nuclear Eng., Baltimore, MD, April 2-6, 2000, pp. 1-5	
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(G)		KLANN, RAYMOND T., ET AL., Development of Semiconductor Detectors For Fast Neutron Radiography, 15 th Int'l. conf. on Applications of Accelerators in Research and Industry, November 2000, pp. 1-4	
(G)		GERSCH, H.K., ET AL., The Effect of Incremental Gamma-Ray Doses and Incremental Neutron Fluences Upon The Performance of Self-Biased ¹⁰ B-Coated High-Purity Epitaxial GaAs Thermal Neutron Detectors, Nuclear Instruments and Methods in Physics Research A 489, February 12, 2002, pp. 85-98	
(G)		MCGREGOR, DOUGLAS S., ET AL., Thin-Film-Coated Detectors For Neutron Detectors, J. of Korean Asso. For Radiation Protection, Vol. 26, 2001, pp. 167-175	
(G)		MCGREGOR, DOUGLAS S., ET AL., Designs For Thin-Film-Coated Semiconductor Thermal Neutron Detectors, University of Michigan, Ann Arbor, Michigan, November 14, 2001, pp. 1-6	
(G)		MCGREGOR, DOULGAS S., ET AL., Recent Results From Thin-Film-Coated Semiconductor Neutron Detectors, Proceedings of SPIE, Vol. 4784, 2002, pp. 164-182	

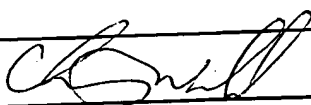
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CG		MCGREGOR, DOUGLAS S., ET AL., Semi-Insulating Bulk GaAs Thermal Neutron Imaging Arrays, IEEE Transactions on Nuclear Science, Vol. 43, No. 3, June 1996, pp. 1357-1364	
CG		ROSE, A., Sputtered Boron Films on Silicon Surface Barrier Detectors, Nuclear Instruments and Methods, 52, 1967, pp. 166-170	
CG		FEIGL B., ET AL., Der Gd-Neutronenzähler, Nuclear Instruments and Methods, 61, Wien, Austria, 1968, pp. 349-356	
CG		MIRESHGHI, A., ET AL., High Efficiency Neutron Sensitive Amorphous Silicon Pixel Detectors, IEEE Transactions on Nuclear Science, Vol. 41, No. 4, August 1994, pp. 915-921	
CG		FOULON, F., ET AL., Neutron Detectors Made From Chemically Vapour Deposited Semiconductors, Proc. MRS, 487, 1998, pp. 591-596	
CG		DULLOO, A.R., ET AL., Radiation Response Testing of Silicon Carbide Semiconductor Neutron Detectors For Monitoring Thermal Neutron Flux, Report 97-9TK1-NUSIC-R1, Westinghouse STC, Pittsburgh, PA, November 18, 1997, pp. 6-1 - 6-14	
CG		KNOLL, GLENN F., Radiation Detection and Measurement, 3 rd Ed. John Wiley & Sons, Inc., New York, 2000, Chapter 14, pp. 505-508	
CG		GARBER, D.I., ET AL., Neutron Cross Sections, 3 rd Edition, Vol. 11, Curves, Brookhaven National Laboratory, Upton, January 1976, pp. 11-13 & pp. 23-24	
CG		MCLANE, VICTORIA, ET AL., Neutron Cross Sections, Vol. 2, Neutron Cross Section Curves, Academic Press, San Diego, CA, 1988, pp. 12-13 & pp. 26-27	
CG		MCGREGOR, DOUGLAS, S., ET AL., Thin-Film-Coated Bulk GaAs Detectors for Thermal and Fast Neutron Measurements, Nuclear Instruments and Methods in Physics Research A 466, 2001, pp. 126-141	
CG		MCGREGOR, DOUGLAS, S., ET AL., Design Considerations for Thin Film Coated Semiconductor Thermal Neutron Detectors -- I: Basics Regarding Alpha Particle Emitting Neutron Reactive Films, Nuclear Instruments & Methods, A 500, 2003, pp. 272-308	

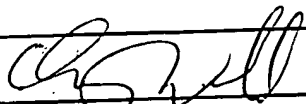
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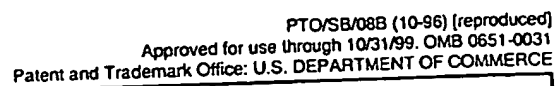
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(G)		PUCKETT, P.R., ET AL., Thin Film Processes II, Chapter V-2, J.L. Vossen and W. Kern, Eds., Academic Press, Boston, 1991, pp. 749	
(G)		SZE, S.M., VLSI Technology, McGraw-Hill, New York, 1983	
(G)		RUSKA, W.S., Microelectronic Processing, McGraw-Hill, New York, 1987	
(G)		WOLF, STANLEY, ET AL., Silicon Processing for the VLSI Era, Lattice Press, Sunset Beach, 1986	
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		http://www.mems-exchange.org/	
		http://physics.nist.gov/MajresProj/rfcell/drawings.html	
(G)		SCHULTEN, J., ET AL., A New Neutron Detector Development Based on Silicon Semiconductor and LiF Converter, Physica B 234-236, 1997, pp. 1084-1086	
(G)		ATOMNAYA ENERGIYA, Soviet Atomic energy, Russian Original, Vol. 62, No. 4, April 1987, pp. 316-319	

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[illegible]

**Examiner
Signature**

Date Considered

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Signature [Signature] **Considered** ☒ **Not Considered** ☐

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